

Epitaxial growth and characterizations of quaternary alloy ferromagnetic semiconductor (In,Ga,Fe)Sb

Kengo Takase^{1,*}, Tomoki Hotta^{1,*}, Kosuke Takiguchi¹, Karumuri Sriharsha¹,
Le Duc Anh^{1,2}, and Masaaki Tanaka^{1,3}

¹*Department of Electrical Engineering and Information Systems, The University of Tokyo*

²*Institute of Engineering Innovation, The University of Tokyo*

³*Center for Spintronics Research Network (CSRN), The University of Tokyo*

*These authors have contributed equally to this work.

E-mail: ktakase@cryst.t.u-tokyo.ac.jp, hotta@cryst.t.u-tokyo.ac.jp

Ferromagnetic semiconductors (FMSs) are promising materials for spintronics applications because of their high compatibility with the semiconductor technology. To realize practical devices operating at room temperature, both p-type and n-type FMSs with high Curie temperature ($T_C > 300$ K) are required. Thus far, although the prototypical FMS (Ga,Mn)As has been intensively studied, it shows only p-type conduction with low T_C (≤ 200 K) [1]. Recently, we have successfully grown Fe-doped III-V FMSs with high T_C ; both p-type (Ga,Fe)Sb with $T_C = 400$ K [2] and n-type (In,Fe)Sb with $T_C = 385$ K [3]. For device applications of these new Fe-doped FMSs, we have to control their fundamental material properties, including the lattice constant, band structure, carrier type, T_C and magnetic anisotropy.

In this work, we have created a new type of Fe-doped quaternary alloy FMS, $(\text{In}_{1-x-y}\text{Ga}_x\text{Fe}_y)\text{Sb}$, with room-temperature ferromagnetism. We grew heterostructures consisting of (from top to bottom) InSb (2 nm) / $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$ (15 nm) / AlSb (100 nm) / AlAs (6 nm) / GaAs (100 nm) on a semi-insulating GaAs(001) substrate by low-temperature molecular-beam epitaxy (LT-MBE). Figure 1(a) shows an X-ray diffraction (XRD) spectrum of our sample and the lattice constant of $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$. The XRD spectrum suggests that the $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$ layer grown by LT-MBE maintains the zinc-blende crystal structure without any other second phases. The lattice constant of $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$ follows the Vegard's law, suggesting that In and Ga atoms reside in the group-III sites. Figure 1(b) shows normalized magnetic circular dichroism (MCD) spectra measured at 5 K with a magnetic field of 1 T, 0.5 T and 0.2 T applied perpendicularly to the film plane. These spectra overlap on a single spectrum in the whole photon-energy range from 1.5 eV to 4.5 eV, indicating intrinsic and homogeneous ferromagnetism in the $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$ film. From the Arrott plot of the MCD intensity vs. magnetic field (MCD - H) curves, we estimate the T_C of the $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$ film to be 320 K. This high T_C and good crystal quality are promising for realizing more materials functionalities and device applications.

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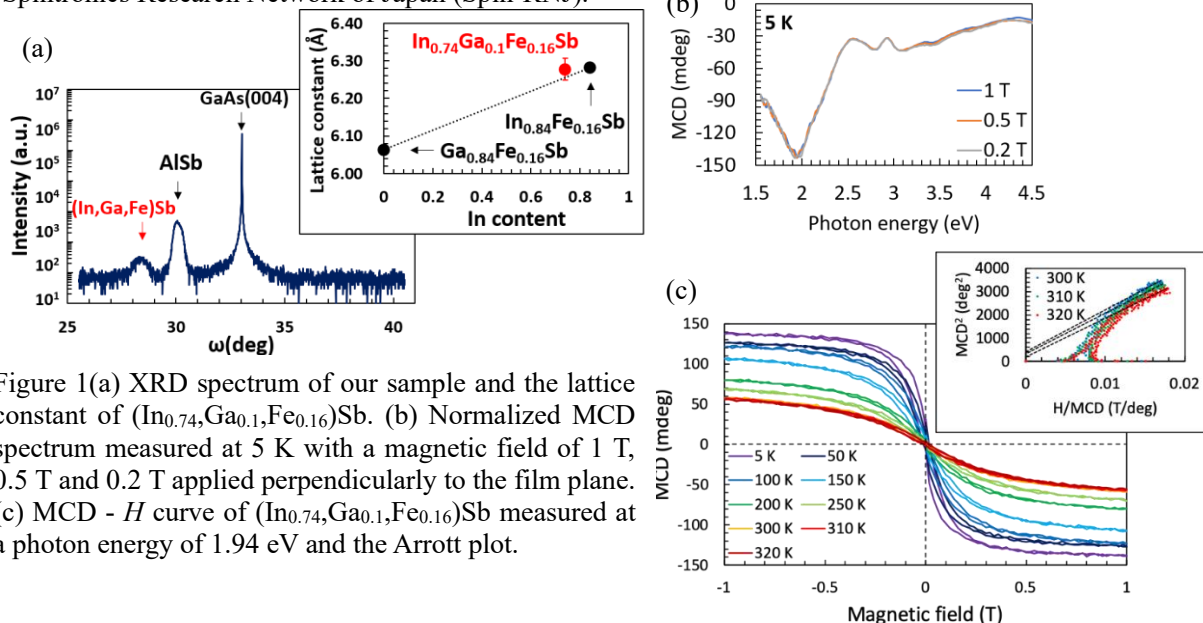


Figure 1(a) XRD spectrum of our sample and the lattice constant of $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$. (b) Normalized MCD spectrum measured at 5 K with a magnetic field of 1 T, 0.5 T and 0.2 T applied perpendicularly to the film plane. (c) MCD - H curve of $(\text{In}_{0.74}\text{Ga}_{0.1}\text{Fe}_{0.16})\text{Sb}$ measured at a photon energy of 1.94 eV and the Arrott plot.

References: [1] L. Chen *et al*, Nano Lett. **11**, 2584 (2011). [2] S. Goel *et al*, Phys. Lett. B **99**, 014431 (2019). [3] N. T. Tu *et al*, Appl. Phys. Express **12**, 103004 (2019).